

# Gouchol Pok

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/2633464/publications.pdf>

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citing authors

#	ARTICLE	IF	CITATIONS
1	A Novel DBSCAN-Based Defect Pattern Detection and Classification Framework for Wafer Bin Map. IEEE Transactions on Semiconductor Manufacturing, 2019, 32, 286-292.	1.7	75
2	Efficient Block Matching for Removing Impulse Noise. IEEE Signal Processing Letters, 2018, 25, 1176-1180.	3.6	12
3	Selective removal of impulse noise based on homogeneity level information. IEEE Transactions on Image Processing, 2003, 12, 85-92.	9.8	215